


<b>Search Notes</b> 	<b>Application/Control No.</b> 10541678	<b>Applicant(s)/Patent Under Reexamination</b> KUNITANI ET AL.
	<b>Examiner</b> Nguyen, Hiep	<b>Art Unit</b> 2816

SEARCHED			
Class	Subclass	Date	Examiner
327	141	05-29-06	Hn

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, see search note	05-29-07	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
327	144,145,147,149,150,152,153,158,163.	05-29-07	Hn